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Pomeranz, I.; Reddy, S.M.;
Computer-Aided Design of Integrated Circuits and Systems, IEEE Transaction
Volume 20, Issue 2, Feb 2001 Page(s):336 - 342
Digital Object Identifier 10.1109/43.908476
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☐ 79. **Vector-restoration-based static compaction using random initial omissio**
Pomeranz, I.; Reddy, S.M.;
Computer-Aided Design of Integrated Circuits and Systems, IEEE Transaction
Volume 23, Issue 11, Nov. 2004 Page(s):1587 - 1592
Digital Object Identifier 10.1109/TCAD.2004.836720
AbstractPlus | References | Full Text: PDF(296 KB)   IEEE JNL
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☐ 80. **Software testing for safety critical applications**
Lingfeng Wang; Tan, K.C.;
Instrumentation & Measurement Magazine, IEEE